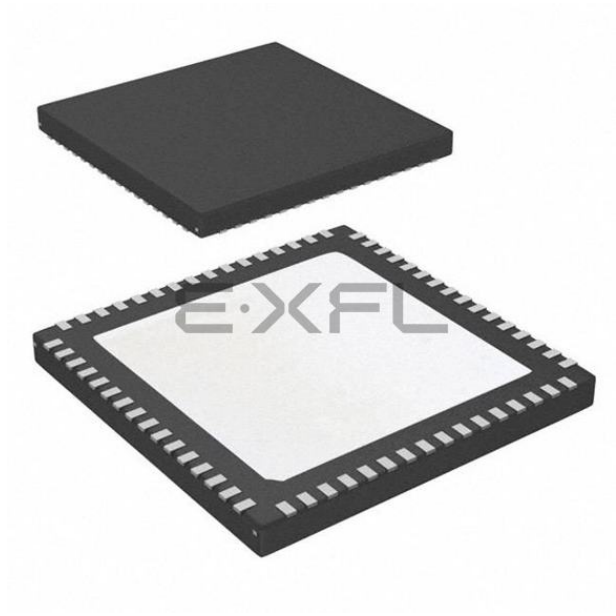

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	EBI/EMI, I²C, IrDA, SmartCard, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-QFN (9x9)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/sim3u136-b-gm

Table 3.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current						
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	33	36.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	10.5	13.3	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	2.0	3.8	mA
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	22	24.9	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	10	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.2	3	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	30.5	35.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	8.5	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.7	—	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	20	23	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	5.3	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.0	—	mA
Power Mode 2[2,3,4]—Core halted with peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	19	22	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.3	—	mA
Power Mode 3[2,3]	I_{DD}	V_{DD} = 1.8 V, T_A = 25 °C	—	175	—	µA
		V_{DD} = 3.0 V, T_A = 25 °C	—	250	—	µA

Notes:
1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Analog Peripheral Supply Currents						
Voltage Regulator (VREG0)	I_{VREGIN}	Normal Mode, T_A = 25 °C BGDIS = 0, SUSEN = 0	—	300	—	µA
		Normal Mode, T_A = 85 °C BGDIS = 0, SUSEN = 0	—	—	650	µA
		Suspend Mode, T_A = 25 °C BGDIS = 0, SUSEN = 1	—	75	—	µA
		Suspend Mode, T_A = 85 °C BGDIS = 0, SUSEN = 1	—	—	115	µA
		Sleep Mode, T_A = 25 °C BGDIS = 1, SUSEN = X	—	90	—	nA
		Sleep Mode, T_A = 85 °C BGDIS = 1, SUSEN = X	—	—	500	nA
Voltage Regulator (VREG0) Sense	$I_{VRSENSE}$	SENSEEN = 1	—	3	—	µA
External Regulator (EXTVREG0)	$I_{EXTVREG}$	Regulator	—	215	250	µA
		Current Sensor	—	7	—	µA
PLL0 Oscillator (PLL0OSC)	I_{PLLOSC}	Operating at 80 MHz	—	1.75	1.86	mA
Low-Power Oscillator (LPOSC0)	I_{LPOSC}	Operating at 20 MHz	—	190	—	µA
		Operating at 2.5 MHz	—	40	—	µA
Low-Frequency Oscillator (LFOSC0)	I_{LFOSC}	Operating at 16.4 kHz, T_A = 25 °C	—	215	—	nA
		Operating at 16.4 kHz, T_A = 85 °C	—	—	500	nA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.5. On-Chip Regulators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
3.3 V Regulator Characteristics (VREG0, Supplied from VREGIN Pin)						
Output Voltage (at VDD pin)	V_{DDOUT}	$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = 0	3.15	3.3	3.4	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = 1	3.15	3.3	3.4	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X I_{DDOUT} = 500 µA	2.3	2.8	3.6	V
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X I_{DDOUT} = 5 mA	2.1	2.65	3.3	V
Output Current (at VDD pin)*	I_{DDOUT}	$4 \le V_{REGIN} \le 5.5$ BGDIS = 0, SUSEN = X	—	—	150	mA
		$4 \le V_{REGIN} \le 5.5$ BGDIS = 1, SUSEN = X	—	—	5	mA
Output Load Regulation	V_{DDLR}	BGDIS = 0	—	0.1	1	mV/mA
Output Capacitance	C_{VDD}		1	—	10	µF

***Note:** Total current VREG0 is capable of providing. Any current consumed by the SiM3C1xx reduces the current available to external devices powered from VDD.

Table 3.12. Capacitive Sense

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Single Conversion Time (Default Configuration)	t_{single}	12-bit Mode	—	25	—	µs
		13-bit Mode	—	27	—	µs
		14-bit Mode	—	29	—	µs
		16-bit Mode	—	33	—	µs
Maximum External Capacitive Load	C_L	Highest Gain Setting (default)	—	45	—	pF
		Lowest Gain Setting	—	500	—	pF
Maximum External Series Impedance	C_L	Highest Gain Setting (default)	—	50	—	kΩ

Table 3.13. Current-to-Voltage Converter (IVC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply Voltage (VDD)	V_{DDIVC}		2.2	—	3.6	V
Input Pin Voltage	V_{IN}		2.2	—	VDD	V
Minimum Input Current (source)	I_{IN}		100	—	—	µA
Integral Nonlinearity	INL_{IVC}		–0.6	—	0.6	%
Full Scale Output	V_{IVCOUT}		—	1.65	—	V
Slope	M_{IVC}	Input Range 1 mA (INxRANGE = 101)	1.55	1.65	1.75	V/mA
		Input Range 2 mA (INxRANGE = 100)	795	830	860	mV/mA
		Input Range 3 mA (INxRANGE = 011)	525	550	570	mV/mA
		Input Range 4 mA (INxRANGE = 010)	390	415	430	mV/mA
		Input Range 5 mA (INxRANGE = 001)	315	330	340	mV/mA
		Input Range 6 mA (INxRANGE = 000)	260	275	285	mV/mA
Settling Time to 0.1%	V_{IVCOUT}		—	—	500	ns

Table 3.14. Voltage Reference Electrical Characteristics

V_{DD} = 1.8 to 3.6 V, –40 to +85 °C unless otherwise specified.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage	V_{REFFS}	–40 to +85 °C, V_{DD} = 1.8–3.6 V	1.62	1.65	1.68	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
On-Chip Precision Reference (VREF0)						
Valid Supply Range	V_{DD}	VREF2X = 0	1.8	—	3.6	V
		VREF2X = 1	2.7	—	3.6	V
Output Voltage	V_{REFP}	25 °C ambient, VREF2X = 0	1.195	1.2	1.205	V
		25 °C ambient, VREF2X = 1	2.39	2.4	2.41	V
Short-Circuit Current	I_{SC}		—	—	10	mA
Temperature Coefficient	TC_{VREFP}		—	25	—	ppm/°C
Load Regulation	LR_{VREFP}	Load = 0 to 200 µA to VREFGND	—	4.5	—	ppm/µA
Load Capacitor	C_{VREFP}	Load = 0 to 200 µA to VREFGND	0.1	—	—	µF
Turn-on Time	$t_{VREFPON}$	4.7 µF tantalum, 0.1 µF ceramic bypass	—	3.8	—	ms
		0.1 µF ceramic bypass	—	200	—	µs
Power Supply Rejection	$PSRR_{VREFP}$	VREF2X = 0	—	320	—	ppm/V
		VREF2X = 1	—	560	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 250 ksps; VREF = 3.0 V	—	5.25	—	µA

Table 3.17. Port I/O (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
P-Channel Source Current Limit (2.7 V ≤ VIOHD ≤ 6 V, V_{OH} = VIOHD – 0.8 V) See Figure 3.2	I_{SRCL}	Mode 0	—	0.8	—	mA
		Mode 1	—	1.25	—	
		Mode 2	—	1.75	—	
		Mode 3	—	2.5	—	
		Mode 4	—	3.5	—	
		Mode 5	—	4.75	—	
		Mode 6	—	7	—	
		Mode 7	—	9.5	—	
		Mode 8	—	14	—	
		Mode 9	—	18.75	—	
		Mode 10	—	28.25	—	
		Mode 11	—	37.5	—	
		Mode 12	—	56.25	—	
		Mode 13	—	75	—	
		Mode 14	—	112.5	—	
		Mode 15	—	150	—	
Total P-Channel Source Current on P4.0-P4.5 (DC)	I_{SRCLT}		—	—	400	mA
Pin Capacitance	C_{IO}		—	30	—	pF
Weak Pull-Up Current in Low Voltage Mode	I_{PU}	V_{IOHD} = 1.8 V	–6	–3.5	–2	µA
		V_{IOHD} = 3.6 V	–30	–20	–10	µA
Weak Pull-Up Current in High Voltage Mode	I_{PU}	V_{IOHD} = 2.7 V	–15	–10	–5	µA
		V_{IOHD} = 6 V	–30	–20	–10	µA
Input Leakage (Pullups off)	I_{LK}		–1	—	1	µA

***Note:** $\overline{\text{RESET}}$ does not drive to logic high. Specifications for $\overline{\text{RESET}}$ V_{OL} adhere to the low drive setting.

Table 3.19. Absolute Maximum Ratings (Continued)

Parameter	Symbol	Test Condition	Min	Max	Unit
Power Dissipation at T_A = 85 °C	P_D	LGA-92 Package	—	570	mW
		TQFP-80 Package	—	500	mW
		QFN-64 Package	—	800	mW
		TQFP-64 Package	—	650	mW
		QFN-40 Package	—	650	mW
***Note:** VSS and VSSHD provide separate return current paths for device supplies, but are not isolated. They must always be connected to the same potential on board.					

4.2. I/O

4.2.1. General Features

The SiM3C1xx ports have the following features:

- Push-pull or open-drain output modes and analog or digital modes.
- Option for high or low output drive strength.
- Port Match allows the device to recognize a change on a port pin value.
- Internal pull-up resistors are enabled or disabled on a port-by-port basis.
- Two external interrupts with up to 16 inputs provide monitoring capability for external signals.
- Internal Pulse Generator Timer (PB2 only) to generate simple square waves.
- A subset of pins can also serve as inputs to the Port Mapped Level Shifters available on the High Drive Pins.

4.2.2. High Drive Pins (PB4)

The High Drive pins have the following additional features:

- Programmable safe state: high, low, or high impedance.
- Programmable drive strength and slew rates.
- Programmable hardware current limiting.
- Powered from a separate source (VIOHD, which can be up to 6 V) from the rest of the device.
- Supports various functions, including GPIO, UART1 pins, EPCA0 pins, or Port Mapped Level Shifting.

4.2.3. 5 V Tolerant Pins (PB3)

The 5 V tolerant pins can be connected to external circuitry operating at voltages above the device supply without needing extra components to shift the voltage level.

4.2.4. Crossbars

The SiM3C1xx devices have two Crossbars with the following features:

- Flexible peripheral assignment to port pins.
- Pins can be individually skipped to move peripherals as needed for design or layout considerations.

The Crossbars have a fixed priority for each I/O function and assign these functions to the port pins. When a digital resource is selected, the least-significant unassigned port pin is assigned to that resource. If a port pin is assigned, the Crossbars skip that pin when assigning the next selected resource. Additionally, the Crossbars will skip port pins whose associated bits in the PBSKIPEN registers are set. This provides some flexibility when designing a system: pins involved with sensitive analog measurements can be moved away from digital I/O and peripherals can be moved around the chip as needed to ease layout constraints.

4.4. Data Peripherals

4.4.1. 16-Channel DMA Controller

The DMA facilitates autonomous peripheral operation, allowing the core to finish tasks more quickly without spending time polling or waiting for peripherals to interrupt. This helps reduce the overall power consumption of the system, as the device can spend more time in low-power modes.

The DMA controller has the following features:

- Utilizes ARM PrimeCell uDMA architecture.
- Implements 16 channels.
- DMA crossbar supports SARADC0, SARADC1, IDAC0, IDAC1, I2C0, I2S0, SPI0, SPI1, USART0, USART1, AES0, EPCA0, external pin triggers, and timers.
- Supports primary, alternate, and scatter-gather data structures to implement various types of transfers.
- Access allowed to all AHB and APB memory space.

4.4.2. 128/192/256-bit Hardware AES Encryption (AES0)

The basic AES block cipher is implemented in hardware. The integrated hardware support for Cipher Block Chaining (CBC) and Counter (CTR) algorithms results in identical performance, memory bandwidth, and memory footprint between the most basic Electronic Codebook (ECB) algorithm and these more complex algorithms. This hardware accelerator translates to more core bandwidth available for other functions or a power savings for low-power applications.

The AES module includes the following features:

- Operates on 4-word (16-byte) blocks.
- Supports key sizes of 128, 192, and 256 bits for both encryption and decryption.
- Generates the round key for decryption operations.
- All cipher operations can be performed without any firmware intervention for a set of 4-word blocks (up to 32 kB).
- Support for various chained and stream-ciphering configurations with XOR paths on both the input and output.
- Internal 4-word FIFOs to facilitate DMA operations.
- Integrated key storage.
- Hardware acceleration for Cipher-Block Chaining (CBC) and Counter (CTR) algorithms utilizing integrated counterblock generation and previous-block caching.

4.4.3. 16/32-bit CRC (CRC0)

The CRC module is designed to provide hardware calculations for Flash memory verification and communications protocols.

The CRC module supports four common polynomials. The supported 32-bit polynomial is 0x04C11DB7 (IEEE 802.3). The three supported 16-bit polynomials are 0x1021 (CCITT-16), 0x3D65 (IEC16-MBus), and 0x8005 (ZigBee, 802.15.4, and USB).

The CRC module includes the following features:

- Support for four common polynomials (one 32-bit and three 16-bit options).
- Byte-level bit reversal for the CRC input.
- Byte-order reorientation of words for the CRC input.
- Word or half-word bit reversal of the CRC result.
- Ability to configure and seed an operation in a single register write.
- Support for single-cycle parallel (unrolled) CRC computation for 32- or 8-bit blocks.
- Capability to CRC 32 bits of data per peripheral bus (APB) clock.
- Support for DMA writes using firmware request mode.

4.7.4. 16-Channel Capacitance-to-Digital Converter (CAPSENSE0)

The Capacitance Sensing module measures capacitance on external pins and converts it to a digital value. The CAPSENSE module has the following features:

- Multiple start-of-conversion sources (CSnTx).
- Option to convert to 12, 13, 14, or 16 bits.
- Automatic threshold comparison with programmable polarity (“less than or equal” or “greater than”).
- Four operation modes: single conversion, single scan, continuous single conversion, and continuous scan.
- Auto-accumulate mode that will take and average multiple samples together from a single start of conversion signal.
- Single bit retry options available to reduce the effect of noise during a conversion.
- Supports channel bonding to monitor multiple channels connected together with a single conversion.
- Scanning option allows the module to convert a single or series of channels and compare against the threshold while the AHB clock is stopped and the core is in a low power mode.

4.7.5. Low Current Comparators (CMP0, CMP1)

The Comparators take two analog input voltages and output the relationship between these voltages (less than or greater than) as a digital signal. The Low Power Comparator module includes the following features:

- Multiple sources for the positive and negative poles, including VDD, VREF, and 8 I/O pins.
- Two outputs are available: a digital synchronous latched output and a digital asynchronous raw output.
- Programmable hysteresis and response time.
- Falling or rising edge interrupt options on the comparator output.

4.7.6. Current-to-Voltage Converter (IVC0)

The IVC module provides inputs to the SARADCn modules so the input current can be measured. The IVC module has the following features:

- Two independent channels.
- Programmable input ranges (1–6 mA full-scale).

Table 6.1. Pin Definitions and alternate functions for SiM3C1x7 (Continued)

Pin Name	Type	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB3.4	5 V Tolerant I/O	16	A9	XBR1	✓	$\overline{OE}$			INT0.9 INT1.9 WAKE.8	CMP0P.4 CMP1P.4
PB3.5	5 V Tolerant I/O	15	B7	XBR1	✓	ALEm			DAC0T2 DAC1T2 INT0.10 INT1.10 WAKE.9	CMP0N.4 CMP1N.4
PB3.6	5 V Tolerant I/O	14	A8	XBR1	✓	CS0			DAC0T3 DAC1T3 INT0.11 INT1.11 WAKE.10	CMP0P.5 CMP1P.5
PB3.7	5 V Tolerant I/O	13	B6	XBR1	✓	$\overline{BE1}$			DAC0T4 DAC1T4 LPT0T1 INT0.12 INT1.12 WAKE.11	CMP0N.5 CMP1N.5
PB3.8	5 V Tolerant I/O	12	A7	XBR1	✓	CS1			DAC0T5 DAC1T5 LPT0T2 INT0.13 INT1.13 WAKE.12	CMP0P.6 CMP1P.6 EXREGSP
PB3.9	5 V Tolerant I/O	11	B5	XBR1	✓	$\overline{BE0}$			DAC0T6 DAC1T6 INT0.14 INT1.14 WAKE.13	CMP0N.6 CMP1N.6 EXREGSN
PB3.10	5 V Tolerant I/O	10	B4	XBR1	✓				INT0.15 INT1.15 WAKE.14	CMP0P.7 CMP1P.7 EXREGOUT
PB3.11	5 V Tolerant I/O	9	B3	XBR1	✓				WAKE.15	CMP0N.7 CMP1N.7 EXREGBD

6.2. SiM3C1x6 Pin Definitions

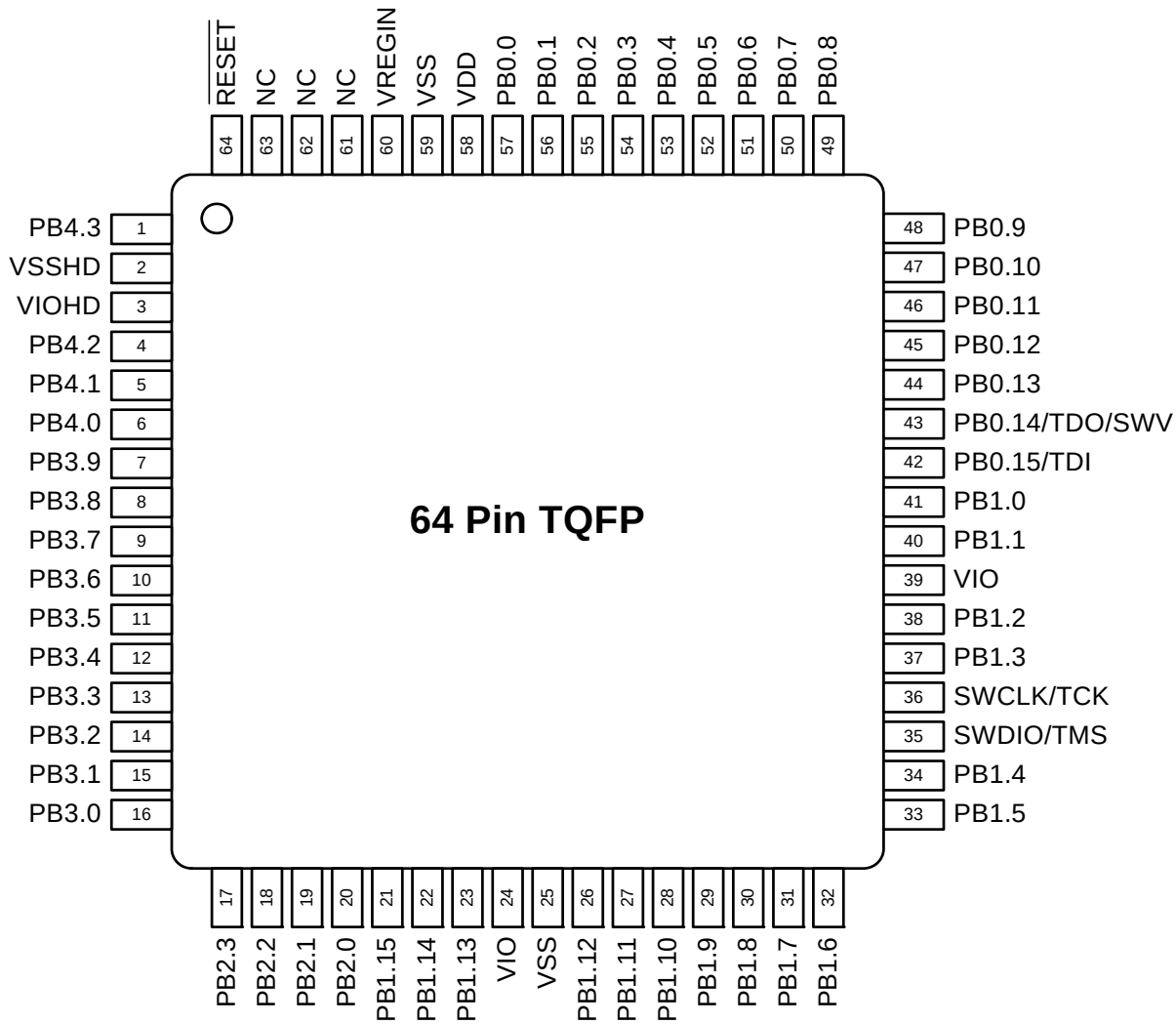

Figure 6.3. SiM3C1x6-GQ Pinout

Table 6.2. Pin Definitions and alternate functions for SiM3C1x6

Pin Name	Type	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
VSS	Ground	25 59							
VDD	Power (Core)	58							
VIO	Power (I/O)	24 39							
VREGIN	Power (Regulator)	60							
VSSHD	Ground (High Drive)	2							
VIOHD	Power (High Drive)	3							
$\overline{\text{RESET}}$	Active-low Reset	64							
SWCLK/TCK	Serial Wire / JTAG	36							
SWDIO/TMS	Serial Wire / JTAG	35							
PB0.0	Standard I/O	57	XBR0	✓					ADC0.2 CS0.1
PB0.1	Standard I/O	56	XBR0	✓					ADC0.3 CS0.2
PB0.2	Standard I/O	55	XBR0	✓					ADC0.4 CS0.3
PB0.3	Standard I/O	54	XBR0	✓					ADC0.5 CS0.4
PB0.4	Standard I/O	53	XBR0	✓					ADC0.6 CS0.5 IVC0.0
PB0.5	Standard I/O	52	XBR0	✓					ADC0.7 CS0.6 IVC0.1
PB0.6	Standard I/O	51	XBR0	✓					ADC0.8 CS0.7 RTC1

Table 6.2. Pin Definitions and alternate functions for SiM3C1x6 (Continued)

Pin Name	Type	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB1.8	Standard I/O	30	XBR0	✓	AD14m/ A6			WAKE.2	ADC1.3 CS0.12
PB1.9	Standard I/O	29	XBR0	✓	AD13m/ A5			WAKE.3	ADC1.2 CS0.13
PB1.10	Standard I/O	28	XBR0	✓	AD12m/ A4			DMA0T1 WAKE.4	ADC1.1 CS0.14
PB1.11	Standard I/O	27	XBR0	✓	AD11m/ A3			DMA0T0 WAKE.5	ADC1.0 CS0.15 PMU_Asleep
PB1.12	Standard I/O	26	XBR0	✓	AD10m/ A2			WAKE.6	
PB1.13	Standard I/O	23	XBR0	✓	AD9m/ A1				
PB1.14	Standard I/O	22	XBR0	✓	AD8m/ A0				
PB1.15	Standard I/O	21	XBR0	✓	AD7m/ D7				
PB2.0	Standard I/O	20	XBR1	✓	AD6m/ D6	LSI0	Yes	INT0.0 INT1.0	
PB2.1	Standard I/O	19	XBR1	✓	AD5m/ D5	LSI1	Yes	INT0.1 INT1.1	
PB2.2	Standard I/O	18	XBR1	✓	AD4m/ D4	LSI2	Yes	INT0.2 INT1.2	CMP0N.0 CMP1N.0 RTC0TCLK_OUT
PB2.3	Standard I/O	17	XBR1	✓	AD3m/ D3	LSI3	Yes	INT0.3 INT1.3	CMP0P.0 CMP1P.0
PB3.0	5 V Tolerant I/O	16	XBR1	✓	AD2m/ D2				CMP0P.1 CMP1P.1
PB3.1	5 V Tolerant I/O	15	XBR1	✓	AD1m/ D1				CMP0N.1 CMP1N.1

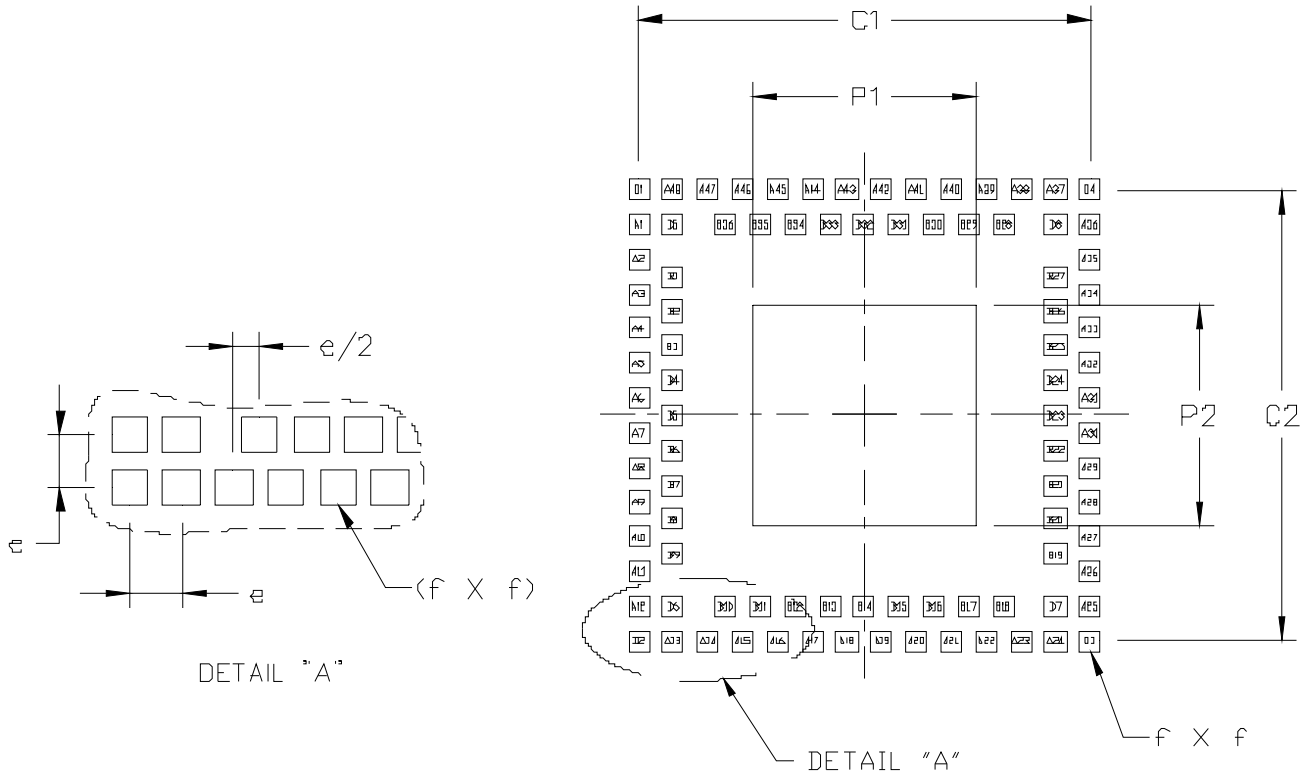

Figure 6.7. LGA-92 Landing Diagram

Table 6.5. LGA-92 Landing Diagram Dimensions

Dimension	Typical	Max
C1	6.50	—
C2	6.50	—
e	0.50	—
f	—	0.35
P1	—	3.20
P2	—	3.20

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. All feature sizes shown are at Maximum Material Condition (MMC) and a card fabrication tolerance of 0.05 mm is assumed.
3. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
4. This land pattern design is based on the IPC-7351 guidelines.

6.6. QFN-64 Package Specifications

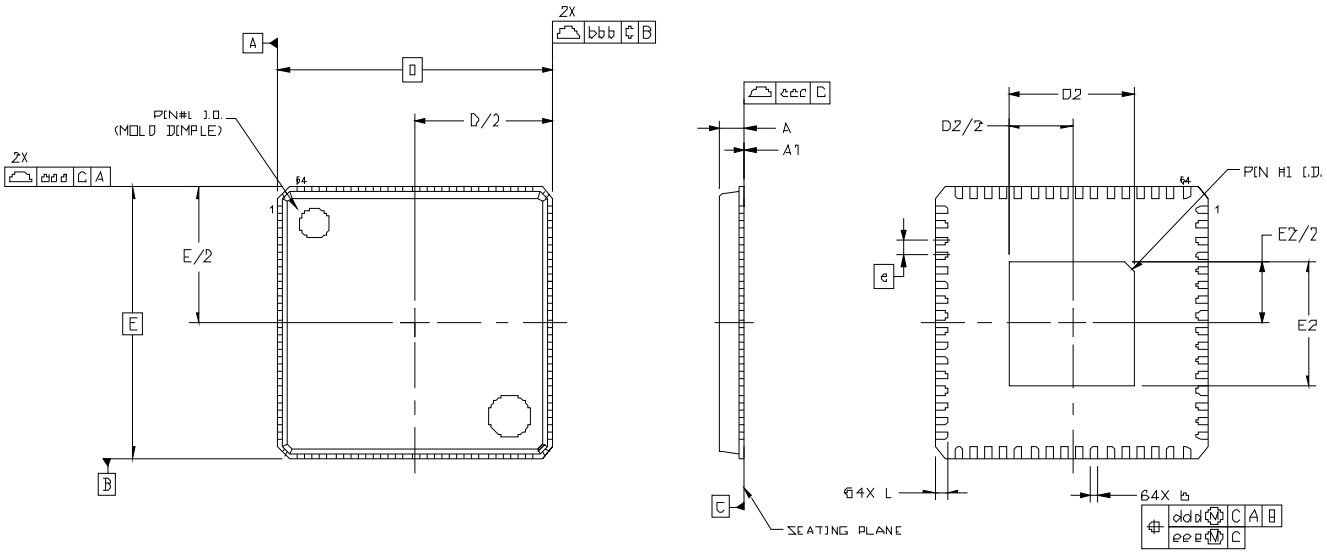

Figure 6.10. QFN-64 Package Drawing

Table 6.8. QFN-64 Package Dimensions

Dimension	Min	Nominal	Max
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		9.00 BSC	
D2	3.95	4.10	4.25
e		0.50 BSC	
E		9.00 BSC	
E2	3.95	4.10	4.25
L	0.30	0.40	0.50
aaa		0.10	
bbb		0.10	
ccc		0.08	
ddd		0.10	
eee		0.05	

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

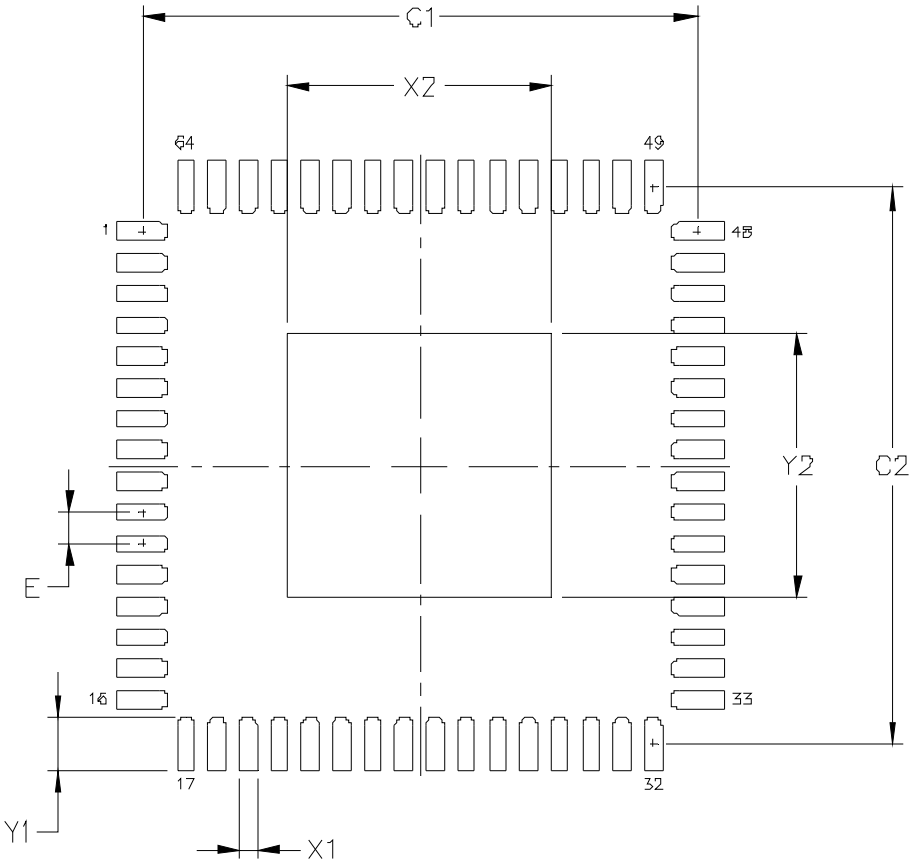

Figure 6.11. QFN-64 Landing Diagram

Table 6.9. QFN-64 Landing Diagram Dimensions

Dimension	mm
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	4.25
Y2	4.25

Notes:
1. All dimensions shown are in millimeters (mm).
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Table 6.10. TQFP-64 Package Dimensions (Continued)

Dimension	Min	Nominal	Max
aaa	—	—	0.20
bbb	—	—	0.20
ccc	—	—	0.08
ddd	—	—	0.08

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MS-026, variant ACD.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

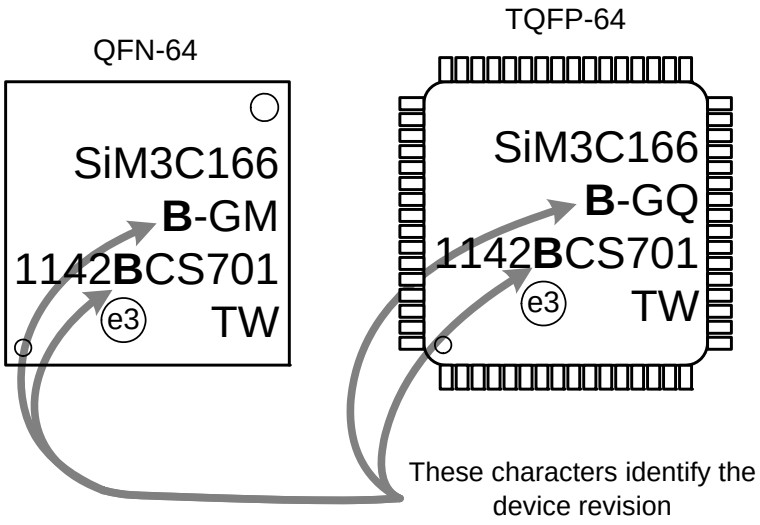

Figure 7.3. SiM3C1x6 Revision Information

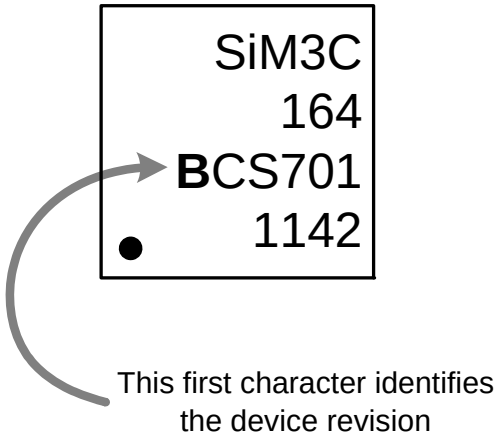

Figure 7.4. SiM3C1x4 Revision Information

7.2. Comparator Rising/Falling Edge Flags in Debug Mode (CMP0, CMP1)

7.2.1. Problem

On Revision A and Revision B devices, if the comparator output is high, the comparator rising and falling edge flags will both be set to 1 upon single-step or exit from debug mode.

7.2.2. Impacts

Firmware using the rising and falling edge flags to make decisions may see a false trigger of the comparator if the output of the comparator is high during a debug session. This does not impact the non-debug operation of the device.

7.2.3. Workaround

There is not a system-agnostic workaround for this issue.

7.2.4. Resolution

This issue exists on Revision A and Revision B devices. It may be corrected in a future device revision.